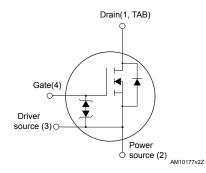


# N-channel 650 V, 36 mΩ typ., 68 A MDmesh DM6 Power MOSFET in a TO247-4 package



TO247-4



#### **Features**

Order code	V <sub>DS</sub>	R <sub>DS(on)</sub> max.	I <sub>D</sub>
STW70N65DM6-4	650 V	40 mΩ	68 A

- Fast-recovery body diode
- Lower R<sub>DS(on)</sub> per area vs previous generation
- · Low gate charge, input capacitance and resistance
- 100% avalanche tested
- Extremely high dv/dt ruggedness
- Zener-protected
- Excellent switching performance thanks to the extra driving source pin

#### **Applications**

· Switching applications

#### **Description**

This high-voltage N-channel Power MOSFET is part of the MDmesh DM6 fast-recovery diode series. Compared with the previous MDmesh fast generation, DM6 combines very low recovery charge ( $Q_{rr}$ ), recovery time ( $t_{rr}$ ) and excellent improvement in  $R_{DS(on)}$  per area with one of the most effective switching behaviors available in the market for the most demanding high-efficiency bridge topologies and ZVS phase-shift converters.



#### Product status link

STW70N65DM6-4

Product summary			
Order code STW70N65DM6-4			
Marking	70N65DM6		
Package	TO247-4		
Packing	Tube		



**Electrical ratings** 

## Table 1. Absolute maximum ratings

Symbol	Parameter	Value	Unit
$V_{GS}$	Gate-source voltage	±25	V
I <sub>D</sub>	Drain current (continuous) at T <sub>C</sub> = 25 °C	68	Α
I <sub>D</sub>	Drain current (continuous) at T <sub>C</sub> = 100 °C	43	Α
I <sub>DM</sub> <sup>(1)</sup>	Drain current (pulsed)	260	Α
P <sub>TOT</sub>	Total power dissipation at T <sub>C</sub> = 25 °C	450	W
dv/dt (2)	Peak diode recovery voltage slope	100	V/ns
di/dt <sup>(2)</sup>	Peak diode recovery current slope	1000	A/µs
dv/dt <sup>(3)</sup>	MOSFET dv/dt ruggedness	100	V/ns
T <sub>STG</sub>	Storage temperature range	-55 to 150	°C
TJ	Operating junction temperature range	-55 (0 150	°C

- 1. Pulse width limited by safe operating area.
- 2.  $I_{SD} \le 68 \; A, \; V_{DS \; (peak)} < V_{(BR)DSS}, \; V_{DD} = 400 \; V.$
- $3. \quad V_{DS} \leq 520 \ V.$

Table 2. Thermal data

Symbol	Parameter	Value	Unit
R <sub>thJC</sub>	Thermal resistance, junction-to-case	0.28	°C/W
R <sub>thJA</sub>	Thermal resistance, junction-to-ambient	50	°C/W

**Table 3. Avalanche characteristics** 

Symbol	Parameter	Value	Unit
I <sub>AR</sub>	Avalanche current, repetitive or not repetitive (t <sub>p</sub> limited by T <sub>J</sub> max)	8	Α
E <sub>AS</sub>	Single pulse avalanche energy (starting $T_J = 25$ °C, $I_D = I_{AR}$ ; $V_{DD} = 50$ V)	1.8	J

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# T<sub>C</sub> = 25 °C unless otherwise specified

**Electrical characteristics** 

Table 4. On/off states

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V <sub>(BR)DSS</sub>	Drain-source breakdown voltage	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 1 mA	650			V
1	Zero gate voltage drain current	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 650 V			10	μА
I <sub>DSS</sub>		V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 650 V, T <sub>C</sub> = 125 °C <sup>(1)</sup>			100	
I <sub>GSS</sub>	Gate-body leakage current	V <sub>DS</sub> = 0 V, V <sub>GS</sub> = ±25 V			±5	μA
V <sub>GS(th)</sub>	Gate threshold voltage	$V_{DS} = V_{GS}$ , $I_{D} = 250 \mu A$	3.25	4	4.75	V
R <sub>DS(on)</sub>	Static drain-source on resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 34 A		36	40	mΩ

<sup>1.</sup> Specified by design, not tested in production.

Table 5. Dynamic characteristics

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
C <sub>iss</sub>	Input capacitance		-	4900	-	
C <sub>oss</sub>	Output capacitance	$V_{DS} = 100 \text{ V}, f = 1 \text{ MHz}, V_{GS} = 0 \text{ V}$	-	280	-	
C <sub>rss</sub>	Reverse transfer capacitance		-	3	-	pF
Coss eq. (1)	Equivalent output capacitance	V <sub>DS</sub> = 0 to 520 V, V <sub>GS</sub> = 0 V	-	859	-	
R <sub>G</sub>	Intrinsic gate resistance	f = 1 MHz, I <sub>D</sub> = 0 A	-	2.3	-	Ω
Qg	Total gate charge	$V_{DD}$ = 520 V, $I_{D}$ = 68 A, $V_{GS}$ = 0 to 10 V (see Figure 14. Test circuit for gate charge behavior)	-	125	-	
Q <sub>gs</sub>	Gate-source charge		-	33	-	nC
Q <sub>gd</sub>	Gate-drain charge		-	56	-	

<sup>1.</sup>  $C_{oss\ eq}$  is defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$ .

Table 6. Switching times (values referred to the TO-247 package)

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t <sub>d(on)</sub>	Turn-on delay time	V <sub>DD</sub> = 325 V, I <sub>D</sub> = 34 A,	-	30.4	-	ns
t <sub>r</sub>	Rise time	$R_G = 4.7 \Omega$ , $V_{GS} = 10 V$	-	52	-	ns
t <sub>d(off)</sub>	Turn-off delay time	(see Figure 13. Switching times test circuit for resistive load and Figure 18. Switching time waveform)	-	107	-	ns
t <sub>f</sub>	Fall time		-	10.8	-	ns

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Table 7. Source-drain diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
$I_{SD}$	Source-drain current		-		68	Α
I <sub>SDM</sub> <sup>(1)</sup>	Source-drain current (pulsed)		-		260	Α
V <sub>SD</sub> <sup>(2)</sup>	Forward on voltage	V <sub>GS</sub> = 0 V, I <sub>SD</sub> = 68 A	-		1.6	V
t <sub>rr</sub>	Reverse recovery time	I <sub>SD</sub> = 68 A, di/dt = 100 A/μs, V <sub>DD</sub> = 60 V (see Figure 15. Test circuit for inductive load switching and diode recovery times)	-	170		ns
Q <sub>rr</sub>	Reverse recovery charge		-	1.08		μC
I <sub>RRM</sub>	Reverse recovery current		-	12.7		Α
t <sub>rr</sub>	Reverse recovery time	I <sub>SD</sub> = 68 A, di/dt = 100 A/μs,	-	308		ns
Q <sub>rr</sub>	Reverse recovery charge	$V_{DD} = 60 \text{ V}, T_{J} = 150 \text{ °C}$	-	4.16		μC
I <sub>RRM</sub>	Reverse recovery current	(see Figure 15. Test circuit for inductive load switching and diode recovery times)	-	27		Α

<sup>1.</sup> Pulse width is limited by safe operating area.

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<sup>2.</sup> Pulsed: pulse duration = 300 μs, duty cycle 1.5%.



### 2.1 Electrical characteristics (curves)

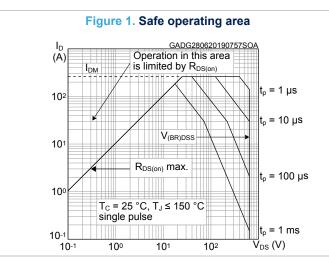
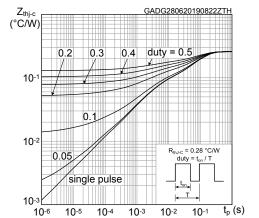


Figure 2. Maximum transient thermal impedance





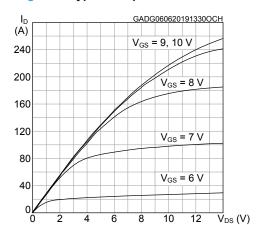


Figure 4. Typical transfer characteristics

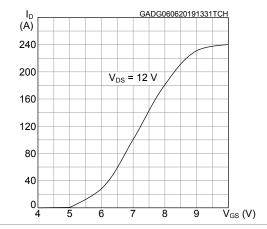


Figure 5. Typical gate charge characteristics

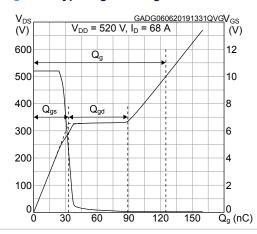
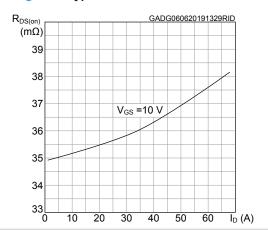


Figure 6. Typical drain-source on-resistance



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Figure 7. Typical capacitance characteristics

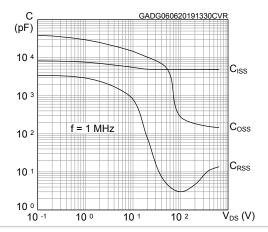


Figure 9. Normalized gate threshold vs temperature

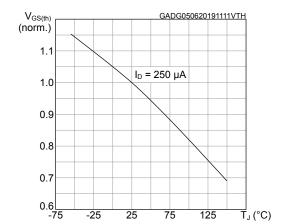


Figure 11. Normalized breakdown voltage vs temperature

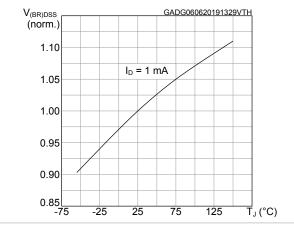


Figure 8. Typical output capacitance stored energy

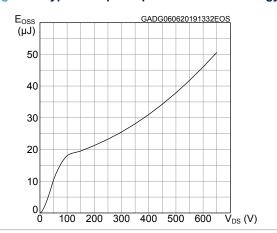


Figure 10. Normalized on-resistance vs. temperature

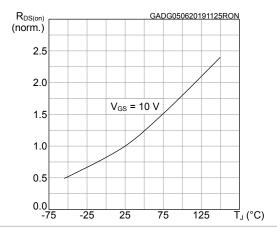
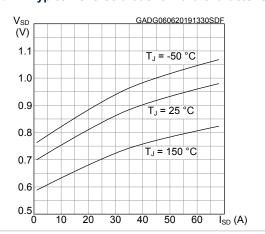


Figure 12. Typical reverse diode forward characteristics



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## **Test circuits**

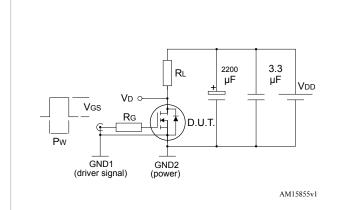


Figure 13. Switching times test circuit for resistive load

Figure 14. Test circuit for gate charge behavior RL I<sub>G</sub>= CONST 2.7 kΩ GND1 GND2

Figure 15. Test circuit for inductive load switching and diode recovery times

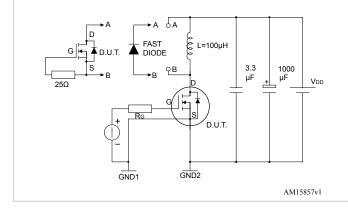


Figure 16. Unclamped inductive load test circuit Vp o 2200 µF 3.3 VDD ΙD GND1

Figure 17. Unclamped inductive waveform

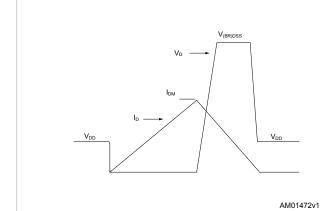
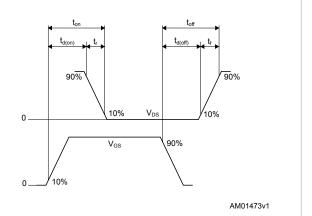


Figure 18. Switching time waveform

GND2



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# 4 Package information

To meet environmental requirements, ST offers these devices in different grades of ECOPACK packages, depending on their level of environmental compliance. ECOPACK specifications, grade definitions, and product status are available at: <a href="https://www.st.com">www.st.com</a>. ECOPACK is an ST trademark.

### 4.1 TO247-4 package information

Figure 19. TO247-4 package outline

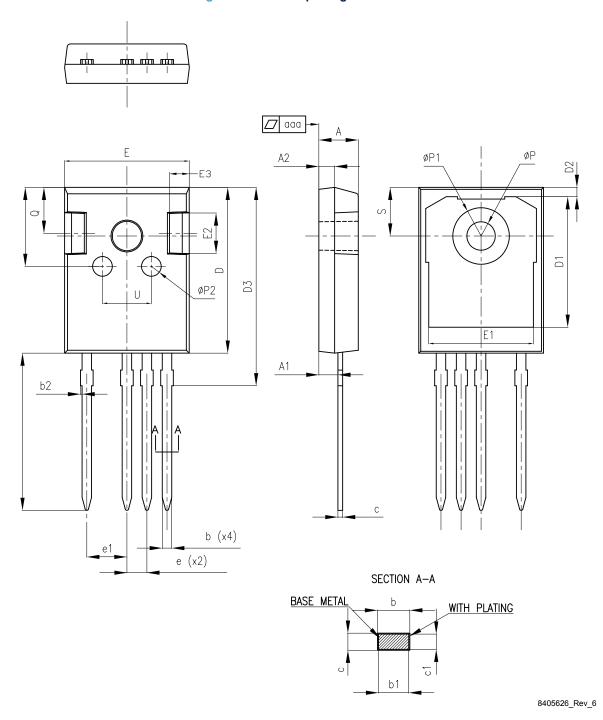




Table 8. TO247-4 mechanical data

Di		mm	
Dim.	Min.	Тур.	Max.
А	4.90	5.00	5.10
A1	2.31	2.41	2.51
A2	1.90	2.00	2.10
b	1.16		1.29
b1	1.15	1.20	1.25
b2	0.00		0.20
С	0.59		0.66
c1	0.58	0.60	0.62
D	20.90	21.00	21.10
D1	16.25	16.55	16.85
D2	1.05	1.20	1.35
D3	24.97	25.12	25.27
E	15.70	15.80	15.90
E1	13.10	13.30	13.50
E2	4.90	5.00	5.10
E3	2.40	2.50	2.60
е	2.44	2.54	2.64
e1	4.98	5.08	5.18
L	19.80	19.92	20.10
Р	3.50	3.60	3.70
P1			7.40
P2	2.40	2.50	2.60
Q	5.60		6.00
S		6.15	
Т	9.80		10.20
U	6.00		6.40
aaa		0.04	0.10

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## **Revision history**

Table 9. Document revision history

Date	Version	Changes
25-Oct-2019	1	First release.
29-Jun-2020	2	Modified Table 1. Absolute maximum ratings.
		Updated Table 6, and Table 7.
28-Feb-2025	3	Updated Section 4.1: TO247-4 package information.
		Minor text changes.

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